Hybrid 4z103 Traveler

December 2, 1999

1 Connectivity

Repairs on shorts:

Fixes for opens: Bus 5H and Bus 4B on Chip 1 wirebonded to jumper field through dummy trace. Calsr on Chip 1 and 2 wirebonded through dummy trace.

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 4Z103 has die: 149-011 149-012 149-013 149-015

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

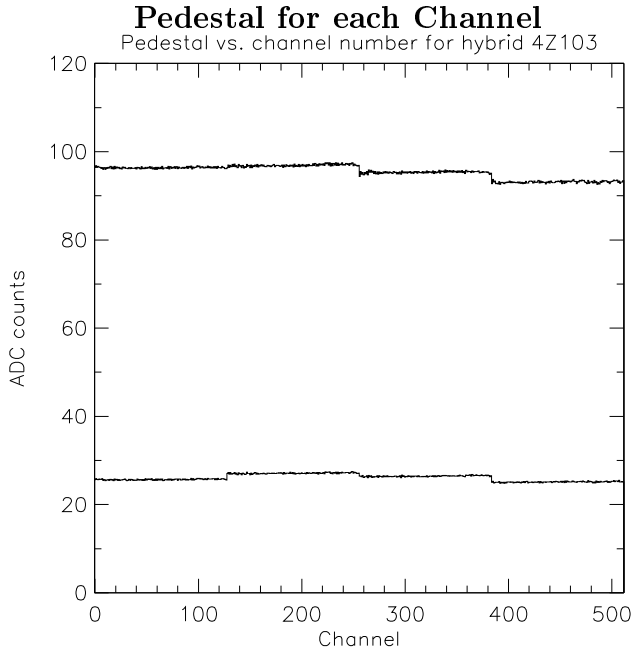
```
% Hybrid 4Z103 classification info. Created 18:17:54 10/12/99

Hybrid 4Z103 quality: good
Chip classification: good good good good
Bad channels: none
Bad cells: none
Random bad capacitors: none
Channels at pedestal needed for DCMS: 34.3 31.7 35.6 35.6
```

4 Comments

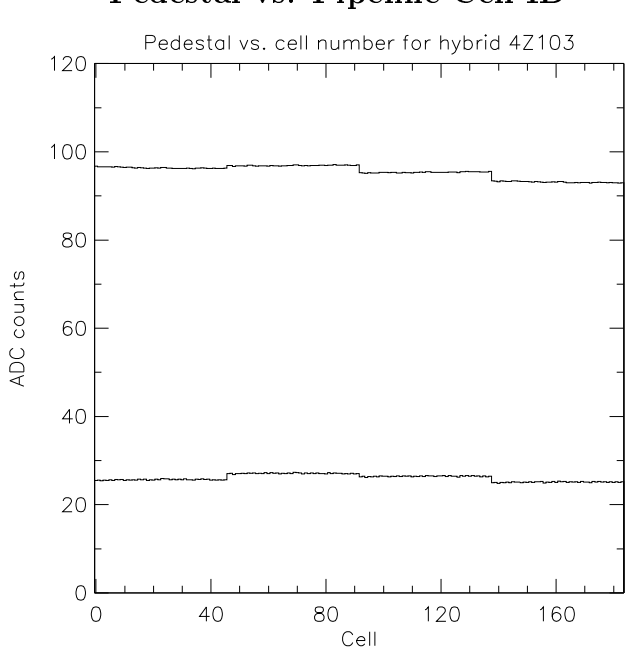
There are two very long wirebonds to the jumper field.
Has redundant FE DVDD and DGND wirebonds.

5 Pedestal

The following plot shows the pedestals vs. channel number with and without charge injection:



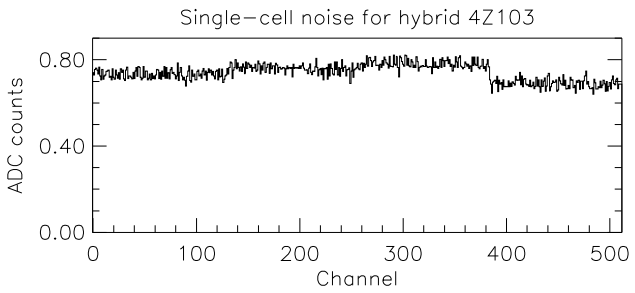
The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

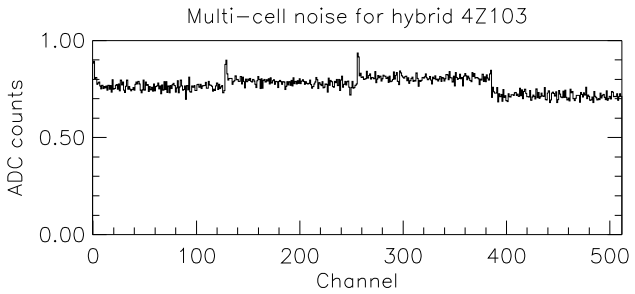


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

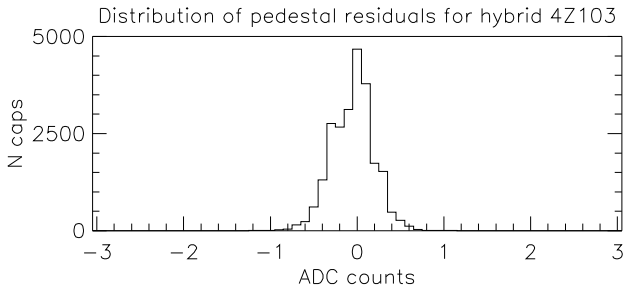
RMS Noise

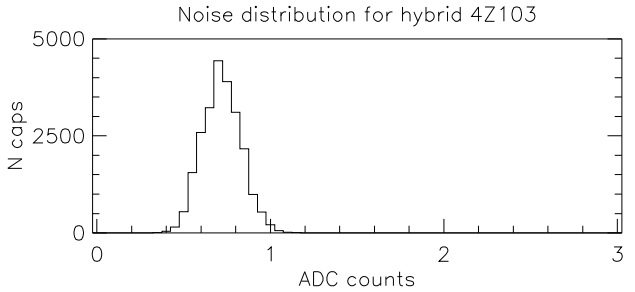




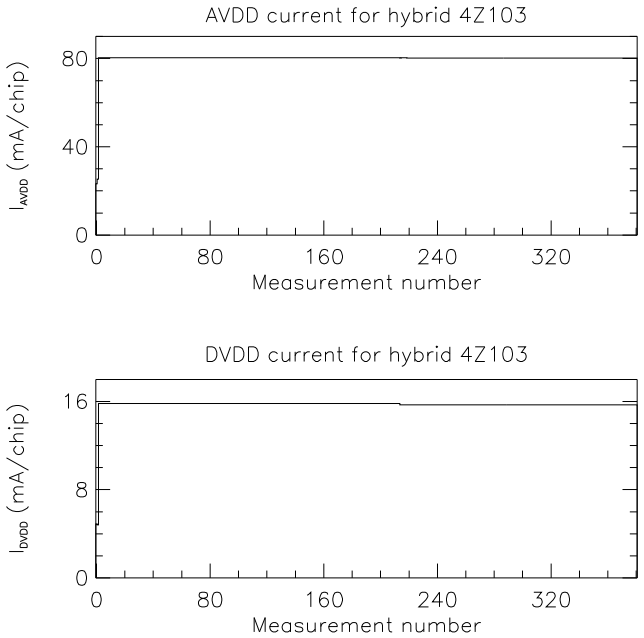
The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in